

Annex B: Measurement Results
Tested Model : Qualy Plus
Report Number: WSCT-ANAB-R&E260700062A-SAR

Measurement Report for Device, BACK, Band 2, UID 10169, Channel 19100 (1900.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Band 2	LTE-FDD, 10169-	1900.000, 19100	7.68	1.44	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

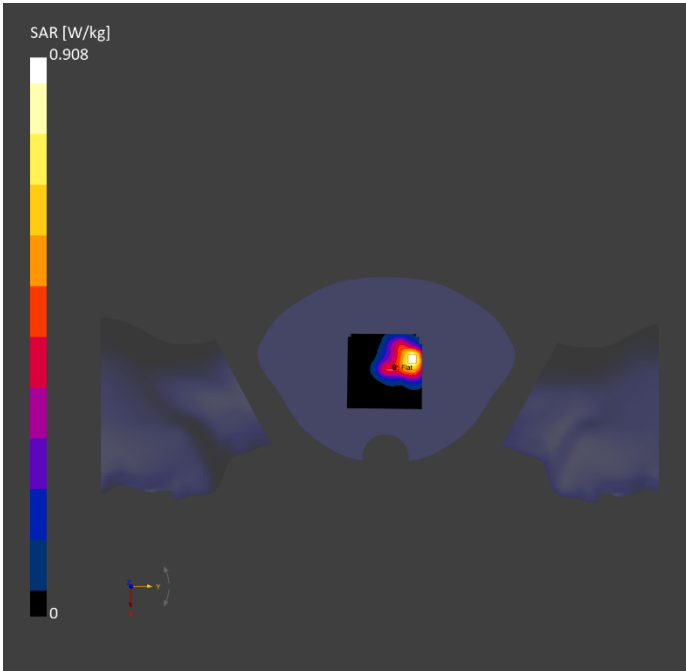
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-27, 10:38	2026-07-27, 10:49
psSAR1g [W/kg]	0.935	0.986
psSAR10g [W/kg]	0.486	0.467
Power Drift [dB]	-0.11	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.2
Dist 3dB Peak [mm]		7.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 4, UID 10169, Channel 20175 (1732.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Band 4	LTE-FDD, 10169-	1732.500, 20175	7.93	1.33	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

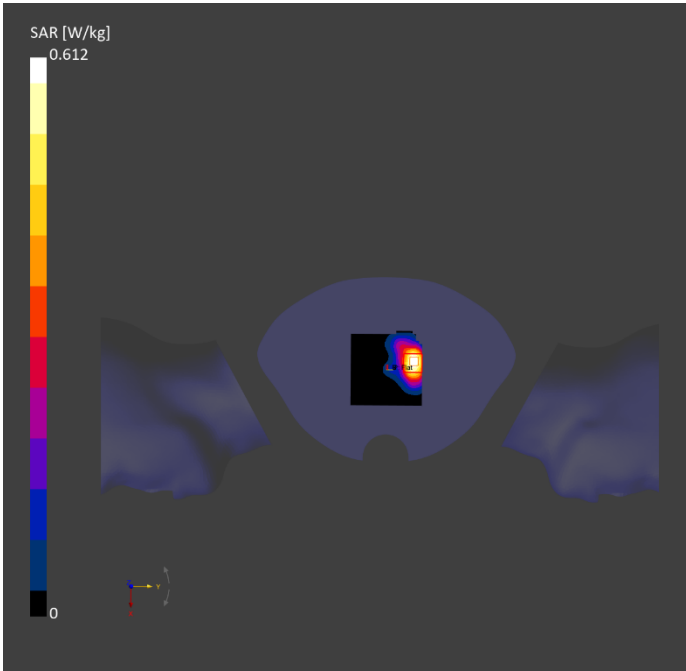
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-26, 10:57	2026-07-26, 11:09
psSAR1g [W/kg]	0.698	0.703
psSAR10g [W/kg]	0.376	0.353
Power Drift [dB]	0.07	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.7
Dist 3dB Peak [mm]		7.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 5, UID 10175, Channel 20525 (836.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Band 5	LTE-FDD, 10175-	836.500, 20525	9.41	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

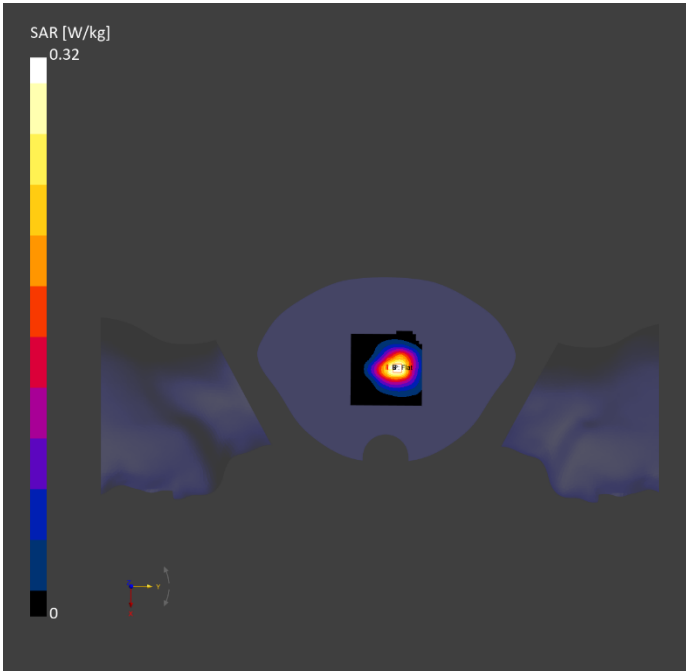
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-24, 09:31	2026-07-24, 09:37
psSAR1g [W/kg]	0.315	0.320
psSAR10g [W/kg]	0.187	0.173
Power Drift [dB]	-0.06	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.1
Dist 3dB Peak [mm]		11.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 7, UID 10169, Channel 21100 (2535.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Band 7	LTE-FDD, 10169-	2535.000, 21100	7.26	1.89	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

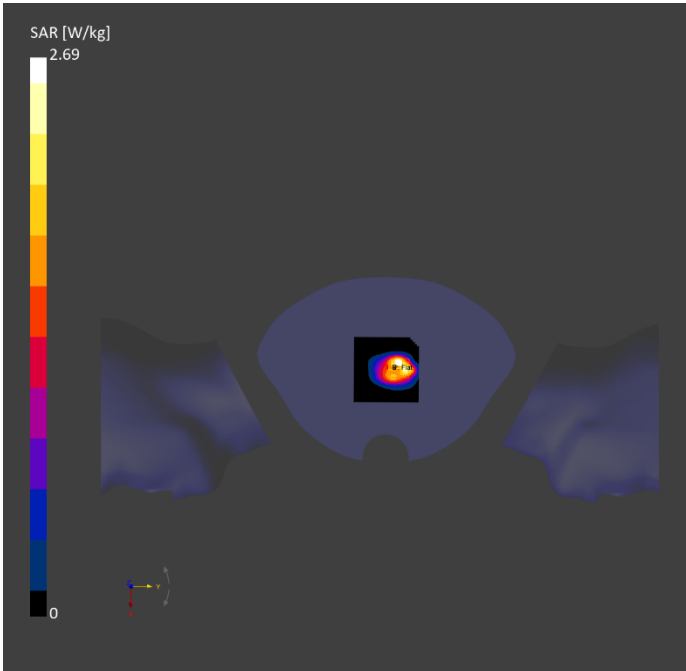
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 08:51	2026-07-29, 09:16
psSAR1g [W/kg]	2.40	2.29
psSAR10g [W/kg]	1.18	0.996
Power Drift [dB]	-0.17	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		70.2
Dist 3dB Peak [mm]		5.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 38, UID 10435, Channel 38000 (2595.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Band 38	LTE-TDD, 10435-	2595.000, 38000	7.26	1.94	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

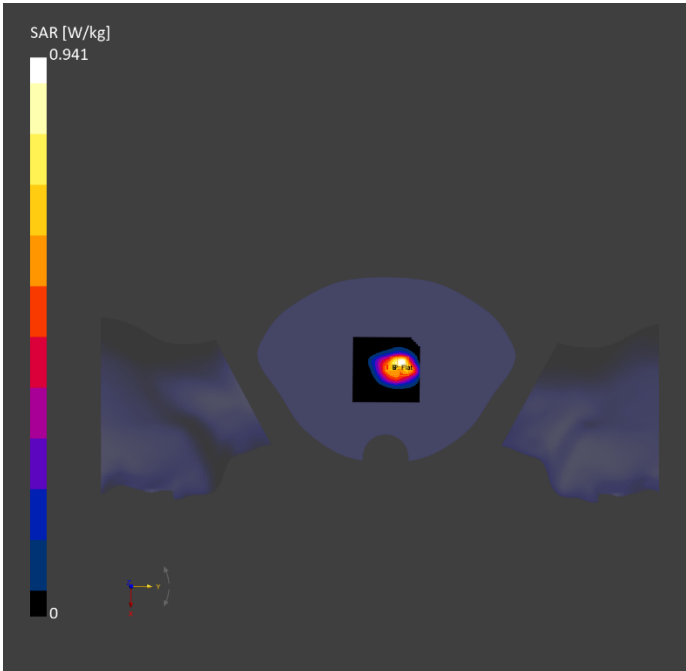
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 10:22	2026-07-29, 10:39
psSAR1g [W/kg]	1.01	0.883
psSAR10g [W/kg]	0.448	0.365
Power Drift [dB]	-0.02	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		71.4
Dist 3dB Peak [mm]		5.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 66, UID 10169, Channel 132572 (1770.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Band 66	LTE-FDD, 10169-	1770.000, 132572	7.93	1.36	41.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

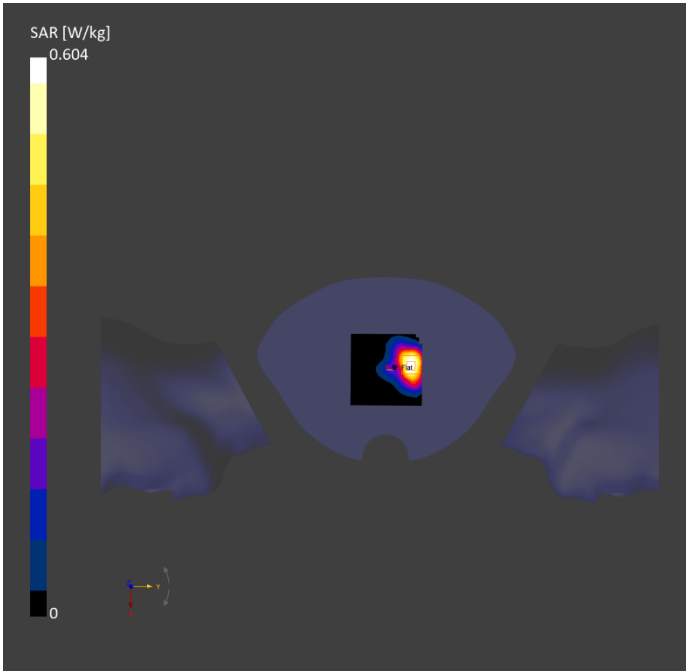
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 10:51	2026-07-29, 10:59
psSAR1g [W/kg]	0.610	0.608
psSAR10g [W/kg]	0.327	0.303
Power Drift [dB]	-0.02	-0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.7
Dist 3dB Peak [mm]		7.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 41, UID 10470, Channel 39700 (2501.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Band 41	LTE-TDD, 10470-	2501.000, 39700	7.26	1.86	40.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

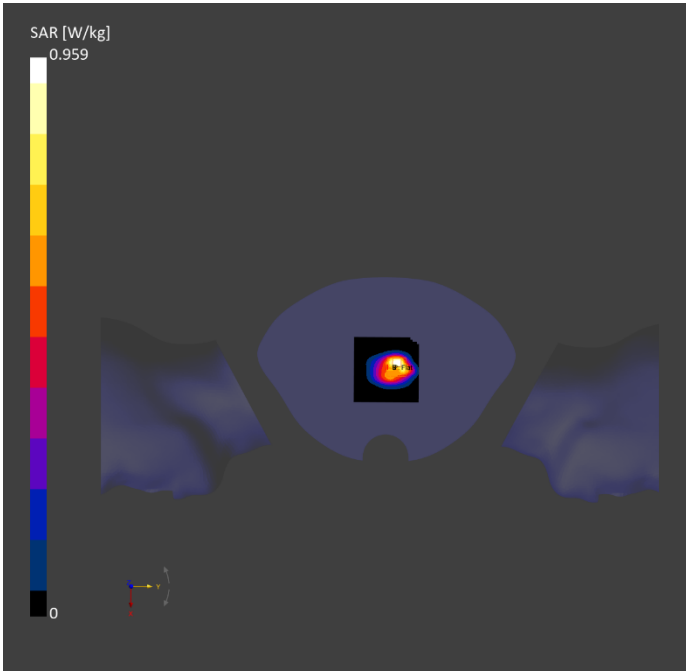
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 11:07	2026-07-29, 11:15
psSAR1g [W/kg]	0.866	0.833
psSAR10g [W/kg]	0.416	0.374
Power Drift [dB]	-0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		71.7
Dist 3dB Peak [mm]		6.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 41, UID 10435, Channel 39750 (2506.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Band 41	LTE-TDD, 10435-	2506.000, 39750	7.26	1.87	40.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

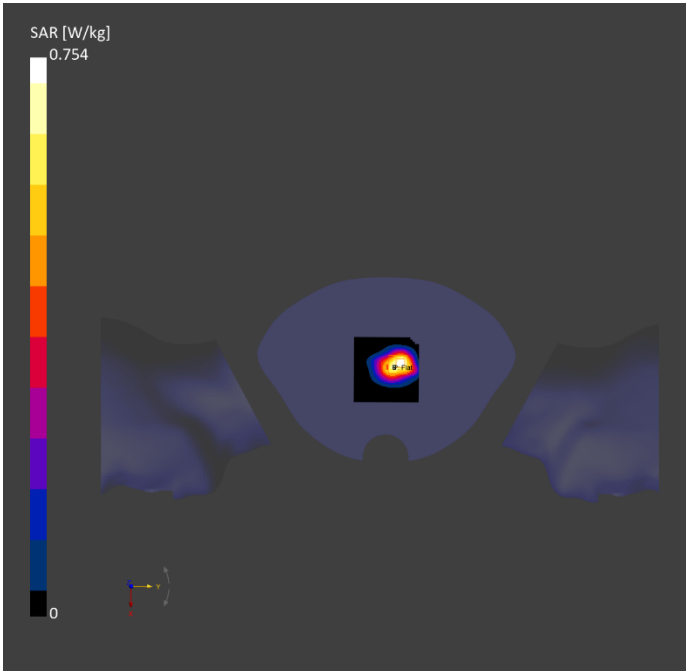
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 11:37	2026-07-29, 11:46
psSAR1g [W/kg]	0.844	0.836
psSAR10g [W/kg]	0.410	0.384
Power Drift [dB]	0.04	-0.13
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		73.0
Dist 3dB Peak [mm]		6.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 41, UID 10435, Channel 40620 (2593.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Band 41	LTE-TDD, 10435-	2593.000, 40620	7.26	1.94	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

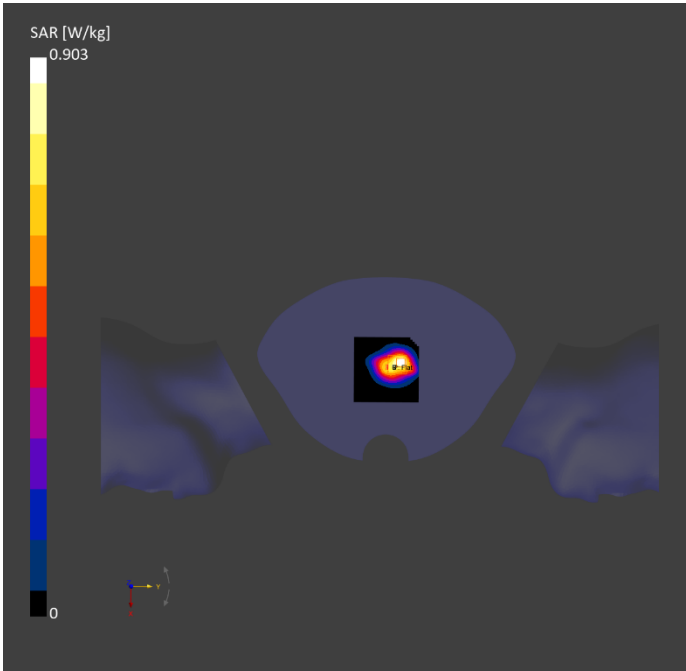
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 11:54	2026-07-29, 12:07
psSAR1g [W/kg]	0.891	0.819
psSAR10g [W/kg]	0.422	0.356
Power Drift [dB]	-0.06	-0.17
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		70.8
Dist 3dB Peak [mm]		5.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 41, UID 10435, Channel 41490 (2680.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Band 41	LTE-TDD, 10435-	2680.000, 41490	7.26	2.01	40.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

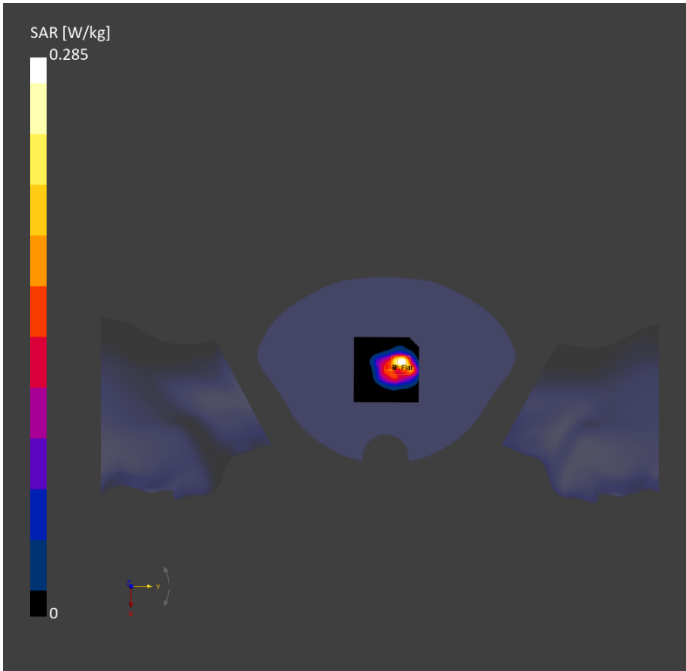
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 12:18	2026-07-29, 12:27
psSAR1g [W/kg]	0.306	0.300
psSAR10g [W/kg]	0.123	0.110
Power Drift [dB]	0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		70.6
Dist 3dB Peak [mm]		5.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 41, UID 10470, Channel 41540 (2685.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Band 41	LTE-TDD, 10470-	2685.000, 41540	7.26	2.01	40.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

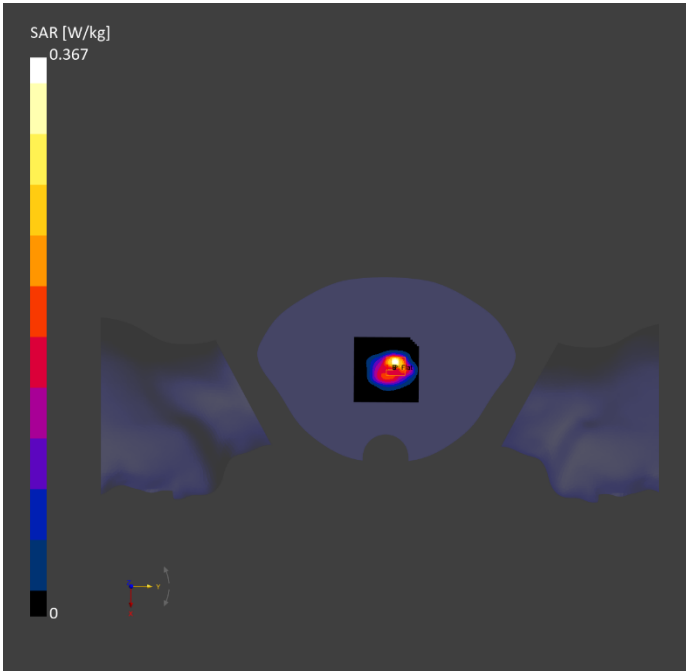
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 13:39	2026-07-29, 13:53
psSAR1g [W/kg]	0.297	0.285
psSAR10g [W/kg]	0.127	0.110
Power Drift [dB]	-0.01	-0.14
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		70.4
Dist 3dB Peak [mm]		5.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 66, UID 10169, Channel 132572 (1770.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Band 66	LTE-FDD, 10169-	1770.000, 132572	7.93	1.36	41.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

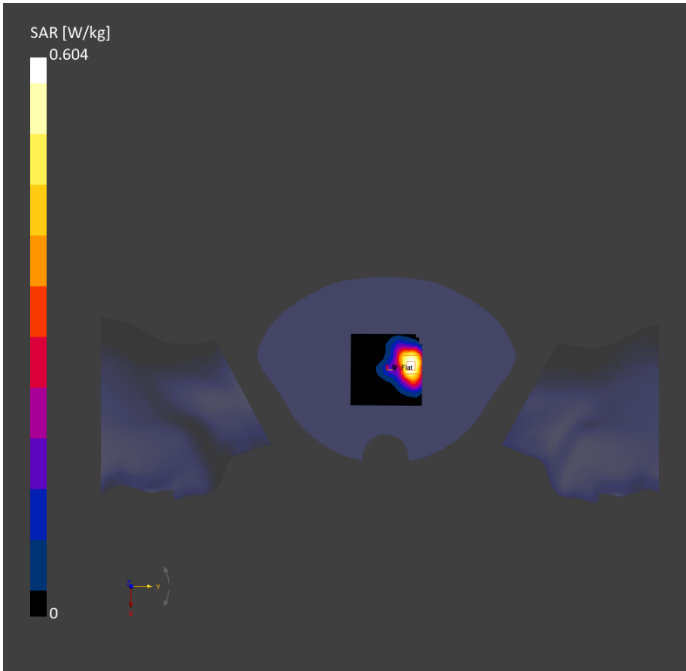
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-26, 13:51	2026-07-26, 13:59
psSAR1g [W/kg]	0.610	0.608
psSAR10g [W/kg]	0.327	0.303
Power Drift [dB]	-0.02	-0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.7
Dist 3dB Peak [mm]		7.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, FRONT, Band 2, UID 10169, Channel 19100 (1900.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 10.00	Band 2	LTE-FDD, 10169-	1900.000, 19100	7.68	1.44	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

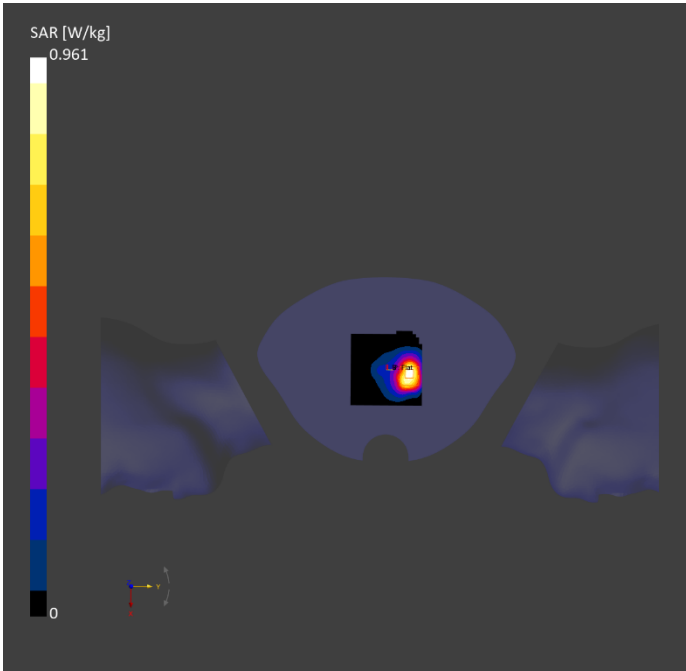
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-27, 14:36	2026-07-27, 14:50
psSAR1g [W/kg]	0.932	1.04
psSAR10g [W/kg]	0.476	0.491
Power Drift [dB]	-0.18	-0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.1
Dist 3dB Peak [mm]		7.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, FRONT, Band 4, UID 10169, Channel 20175 (1732.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 10.00	Band 4	LTE-FDD, 10169-	1732.500, 20175	7.93	1.33	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

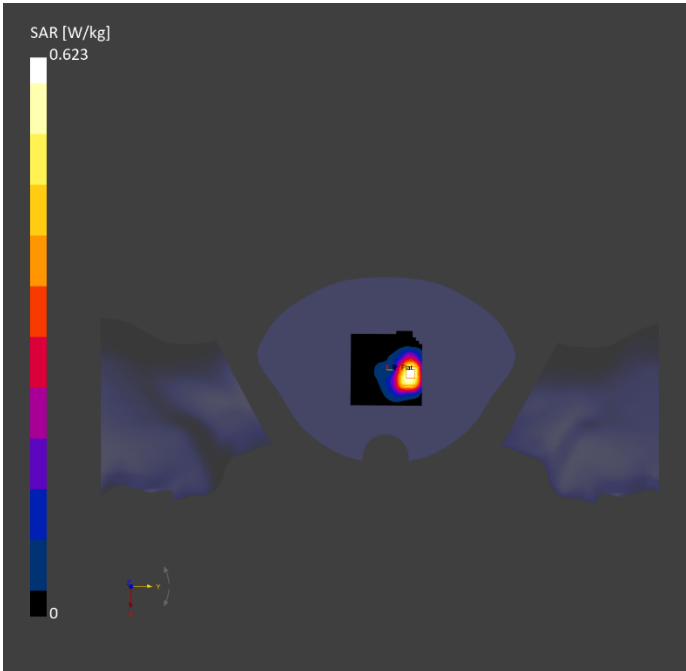
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-26, 14:56	2026-07-27, 15:13
psSAR1g [W/kg]	0.651	0.754
psSAR10g [W/kg]	0.333	0.356
Power Drift [dB]	-0.09	-24.23
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.0
Dist 3dB Peak [mm]		6.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, FRONT, Band 5, UID 10175, Channel 20525 (836.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 10.00	Band 5	LTE-FDD, 10175-	836.500, 20525	9.41	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

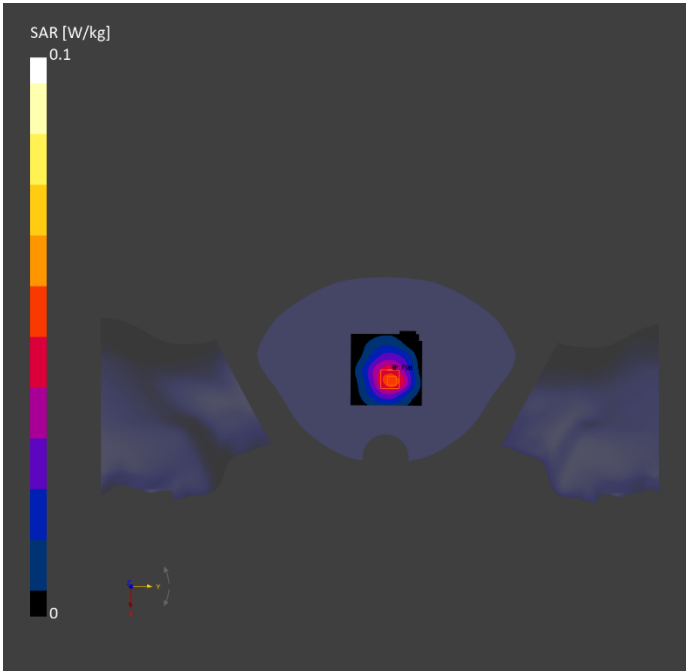
	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-24, 15:18	2026-07-14, 15:29
psSAR1g [W/kg]	0.056	0.049
psSAR10g [W/kg]	0.036	0.031
Power Drift [dB]	-0.34	-0.21
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.1
Dist 3dB Peak [mm]		16.7

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, FRONT, Band 7, UID 10169, Channel 21100 (2535.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 10.00	Band 7	LTE-FDD, 10169-	2535.000, 21100	7.26	1.89	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

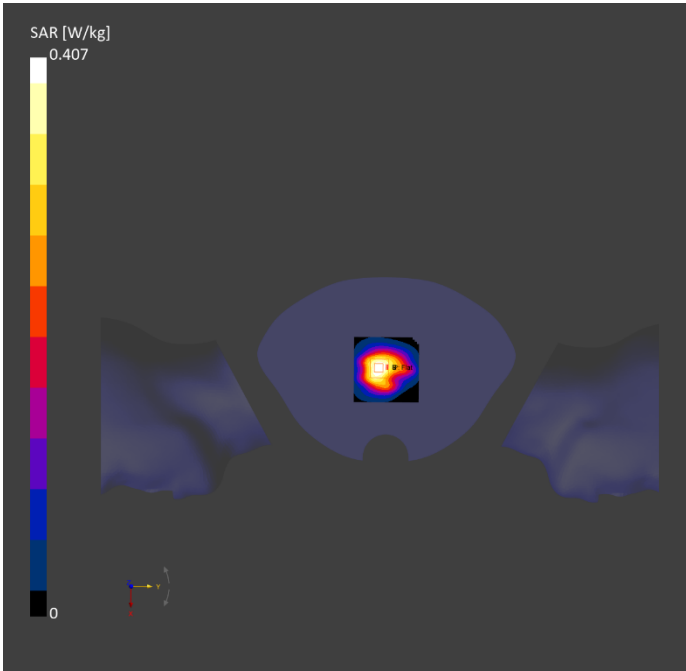
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 14:28	2026-07-29, 14:38
psSAR1g [W/kg]	0.397	0.327
psSAR10g [W/kg]	0.221	0.186
Power Drift [dB]	-0.66	-0.33
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.7
Dist 3dB Peak [mm]		17.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, FRONT, Band 38, UID 10435, Channel 38000 (2595.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 10.00	Band 38	LTE-TDD, 10435-	2595.000, 38000	7.26	1.94	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

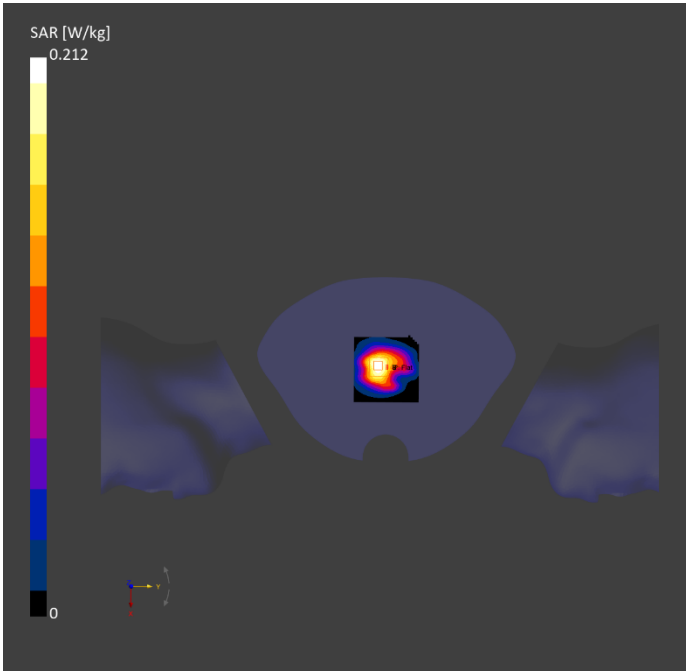
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 15:24	2026-07-29, 15:37
psSAR1g [W/kg]	0.211	0.212
psSAR10g [W/kg]	0.114	0.118
Power Drift [dB]	0.02	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.4
Dist 3dB Peak [mm]		16.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, FRONT, Band 41, UID 10470, Channel 39700 (2501.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 10.00	Band 41	LTE-TDD, 10470-	2501.000, 39700	7.26	1.86	40.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

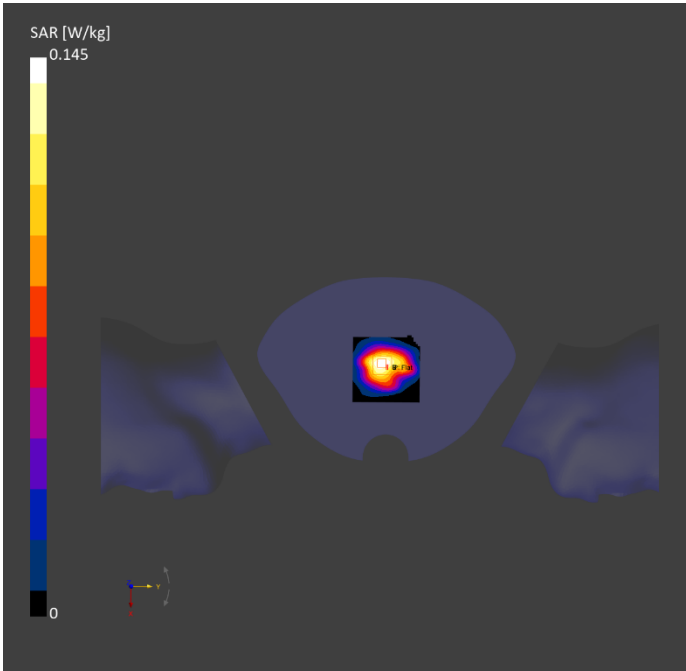
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 15:46	2026-07-29, 15:55
psSAR1g [W/kg]	0.144	0.144
psSAR10g [W/kg]	0.080	0.082
Power Drift [dB]	0.05	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.4
Dist 3dB Peak [mm]		14.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, FRONT, Band 41, UID 10435, Channel 39750 (2506.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 10.00	Band 41	LTE-TDD, 10435-	2506.000, 39750	7.26	1.87	40.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

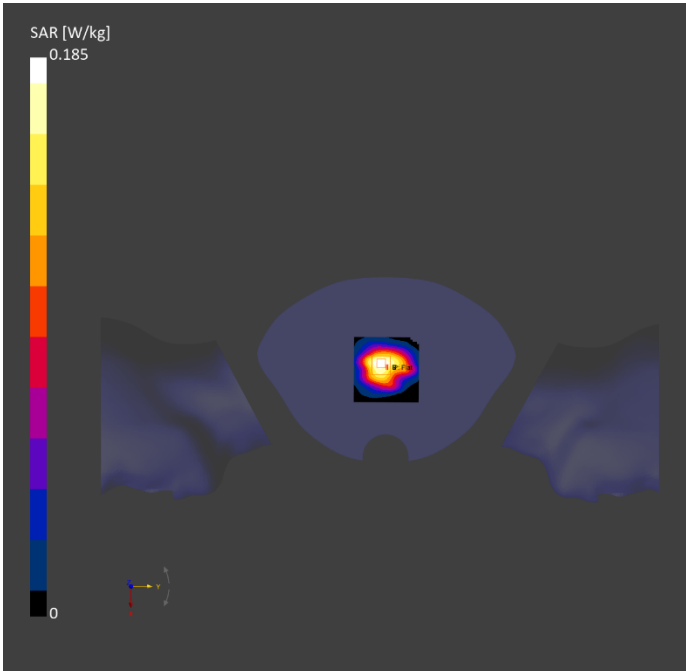
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 16:05	2026-07-29, 16:14
psSAR1g [W/kg]	0.177	0.164
psSAR10g [W/kg]	0.099	0.093
Power Drift [dB]	-0.33	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.3
Dist 3dB Peak [mm]		15.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, FRONT, Band 41, UID 10435, Channel 40620 (2593.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 10.00	Band 41	LTE-TDD, 10435-	2593.000, 40620	7.26	1.94	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

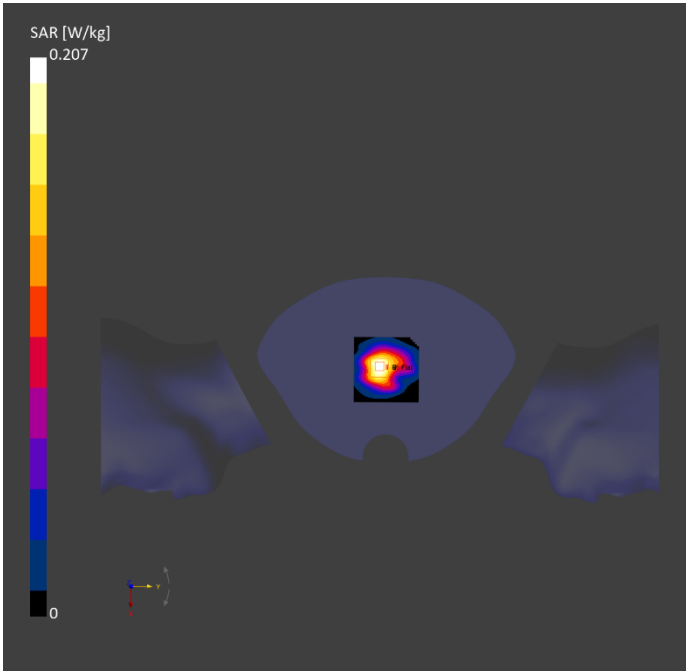
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 17:06	2026-07-29, 17:20
psSAR1g [W/kg]	0.209	0.213
psSAR10g [W/kg]	0.113	0.119
Power Drift [dB]	-0.01	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.9
Dist 3dB Peak [mm]		16.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, FRONT, Band 41, UID 10435, Channel 41490 (2680.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 10.00	Band 41	LTE-TDD, 10435-	2680.000, 41490	7.26	2.01	40.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

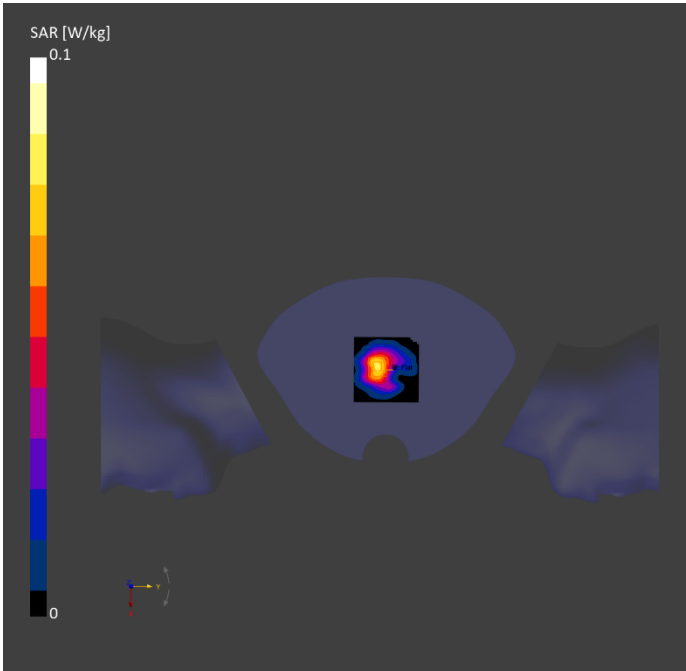
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 17:23	2026-07-29, 17:37
psSAR1g [W/kg]	0.074	0.071
psSAR10g [W/kg]	0.038	0.038
Power Drift [dB]	-0.05	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.8
Dist 3dB Peak [mm]		13.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, FRONT, Band 41, UID 10470, Channel 41540 (2685.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 10.00	Band 41	LTE-TDD, 10470-	2685.000, 41540	7.26	2.01	40.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

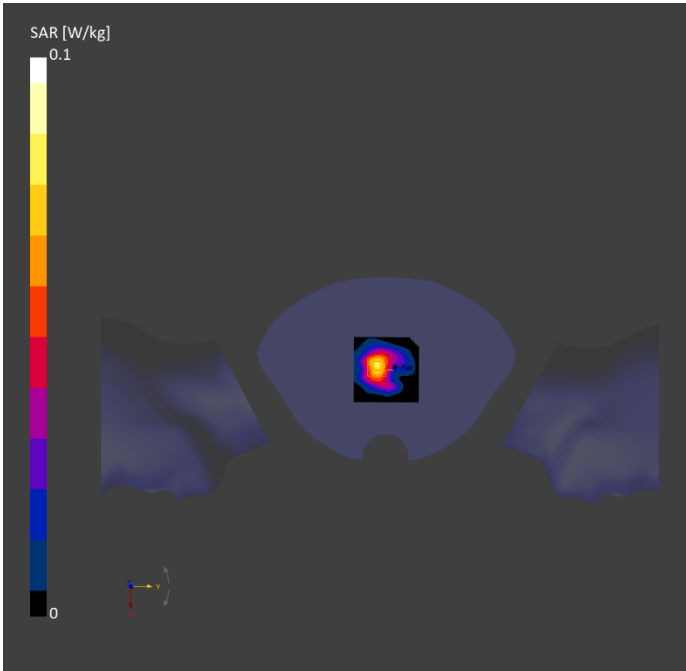
	Area Scan	Zoom Scan
Grid Extents [mm]	80.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 17:52	2026-07-29, 18:06
psSAR1g [W/kg]	0.074	0.072
psSAR10g [W/kg]	0.038	0.037
Power Drift [dB]	0.05	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.0
Dist 3dB Peak [mm]		13.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, FRONT, Band 66, UID 10169, Channel 132572 (1770.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 50.0 x 25.0		

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 10.00	Band 66	LTE-FDD, 10169-	1770.000, 132572	7.93	1.36	41.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2209	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7955, 2025-09-30	DAE4ip Sn1924, 2025-09-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-29, 18:29	2026-07-29, 18:50
psSAR1g [W/kg]	0.436	0.594
psSAR10g [W/kg]	0.244	0.284
Power Drift [dB]	0.05	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.9
Dist 3dB Peak [mm]		7.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		

